

## 20V N+N-Channel Enhancement Mode MOSFET

### Description

The AP9926B uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 20V$   $I_D = 6.2A$

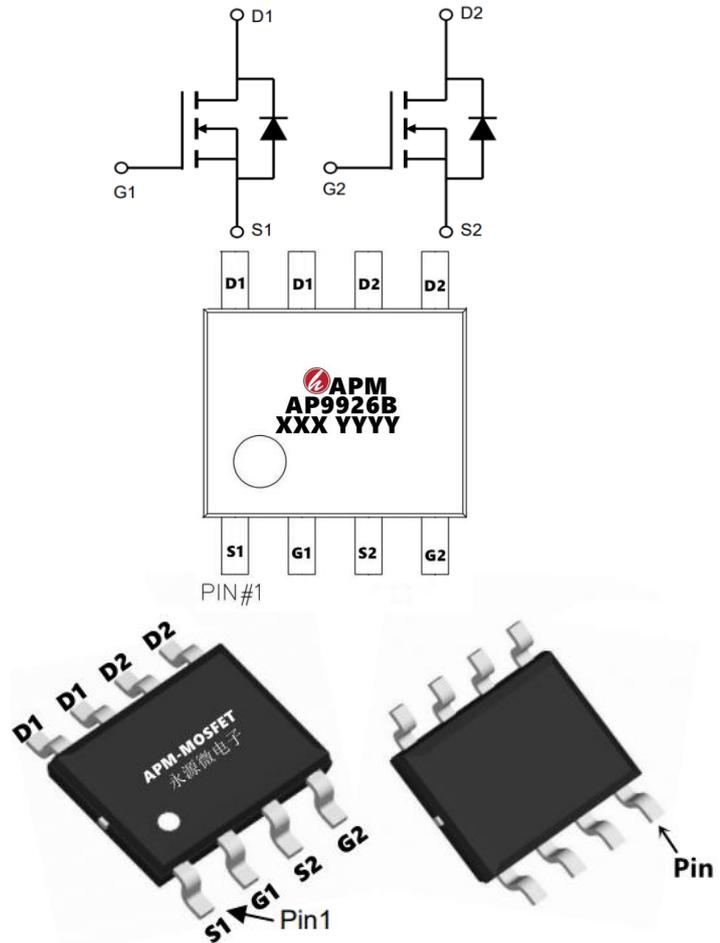
$R_{DS(ON)} < 25m\Omega$  @  $V_{GS}=4.5V$  (Type: 20m $\Omega$ )

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

| Product ID | Pack   | Marking          | Qty(PCS) |
|------------|--------|------------------|----------|
| AP9926B    | SOP-8L | AP9926B XXX YYYY | 3000     |

### Absolute Maximum Ratings ( $T_C=25^\circ C$ unless otherwise noted)

| Symbol                 | Parameter  | Rating     | Units        |
|------------------------|--|------------|--------------|
| $V_{DS}$               | Drain-Source Voltage                             | 20         | V            |
| $V_{GS}$               | Gate-Source Voltage                              | $\pm 12$   | V            |
| $I_D @ T_A=25^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V^1$      | 6.2        | A            |
| $I_D @ T_A=70^\circ C$ | Continuous Drain Current, $V_{GS} @ 4.5V^1$      | 3.8        | A            |
| $I_{DM}$               | Pulsed Drain Current <sup>2</sup>                | 24         | A            |
| $P_D @ T_A=25^\circ C$ | Total Power Dissipation <sup>3</sup>             | 1          | W            |
| $T_{STG}$              | Storage Temperature Range                        | -55 to 150 | $^\circ C$   |
| $T_J$                  | Operating Junction Temperature Range             | -55 to 150 | $^\circ C$   |
| $R_{\theta JA}$        | Thermal Resistance Junction-ambient <sup>1</sup> | 85         | $^\circ C/W$ |
| $R_{\theta JC}$        | Thermal Resistance Junction-Case <sup>1</sup>    | 80         | $^\circ C/W$ |

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### Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)

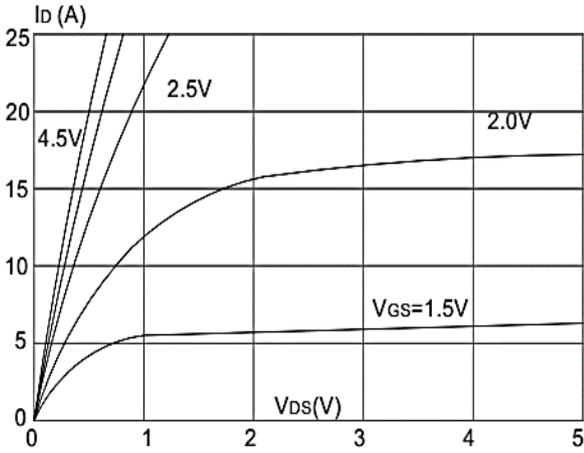
| Symbol       | Parameter                                      | Conditions                                       | Min. | Typ. | Max.      | Unit       |
|--------------|--|--|------|------|-----------|------------|
| $BV_{DSS}$   | Drain-Source Breakdown Voltage                 | $V_{GS}=0V, I_D=250\mu A$                        | 20   | 22   | ---       | V          |
| $R_{DS(ON)}$ | Static Drain-Source On-Resistance <sup>2</sup> | $V_{GS}=4.5V, I_D=4A$                            | ---  | 20   | 25        | m $\Omega$ |
|              |  | $V_{GS}=2.5V, I_D=3A$                            | ---  | 25   | 35        |            |
| $V_{GS(th)}$ | Gate Threshold Voltage                         | $V_{GS}=V_{DS}, I_D=250\mu A$                    | 0.5  | 0.75 | 1.2       | V          |
| $I_{DSS}$    | Drain-Source Leakage Current                   | $V_{DS}=16V, V_{GS}=0V, T_J=25^\circ\text{C}$    | ---  | ---  | 1         | uA         |
|              |  | $V_{DS}=16V, V_{GS}=0V, T_J=55^\circ\text{C}$    | ---  | ---  | 5         |            |
| $I_{GSS}$    | Gate-Source Leakage Current                    | $V_{GS}=\pm 12V, V_{DS}=0V$                      | ---  | ---  | $\pm 100$ | nA         |
| $g_{fs}$     | Forward Transconductance                       | $V_{DS}=5V, I_D=3A$                              | ---  | 10.5 | ---       | S          |
| $Q_g$        | Total Gate Charge (4.5V)                       | $V_{DS}=15V, V_{GS}=4.5V, I_D=3A$                | ---  | 4.6  | ---       | nC         |
| $Q_{gs}$     | Gate-Source Charge                             |  | ---  | 0.7  | ---       |            |
| $Q_{gd}$     | Gate-Drain Charge                              |  | ---  | 1.5  | ---       |            |
| $T_{d(on)}$  | Turn-On Delay Time                             | $V_{DD}=10V, V_{GS}=4.5V, R_G=3.3\Omega, I_D=3A$ | ---  | 1.6  | ---       | ns         |
| $T_r$        | Rise Time                                      |  | ---  | 42   | ---       |            |
| $T_{d(off)}$ | Turn-Off Delay Time                            |  | ---  | 14   | ---       |            |
| $T_f$        | Fall Time                                      |  | ---  | 7    | ---       |            |
| $C_{iss}$    | Input Capacitance                              | $V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$           | ---  | 310  | ---       | pF         |
| $C_{oss}$    | Output Capacitance                             |  | ---  | 49   | ---       |            |
| $C_{rss}$    | Reverse Transfer Capacitance                   |  | ---  | 35   | ---       |            |
| $I_S$        | Continuous Source Current <sup>1,4</sup>       | $V_G=V_D=0V, \text{Force Current}$               | ---  | ---  | 3.6       | A          |
| $V_{SD}$     | Diode Forward Voltage <sup>2</sup>             | $V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$        | ---  | ---  | 1.2       | V          |

#### Note :

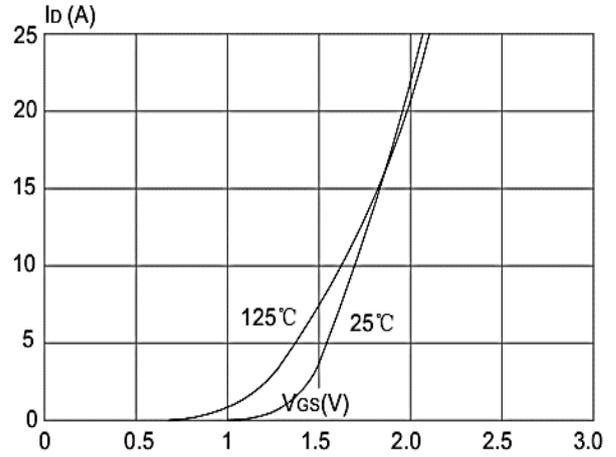
- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The power dissipation is limited by 150 $^\circ\text{C}$  junction temperature
- 4、The data is theoretically the same as  $I_D$  and  $I_{DM}$  , in real applications , should be limited by total power dissipation.

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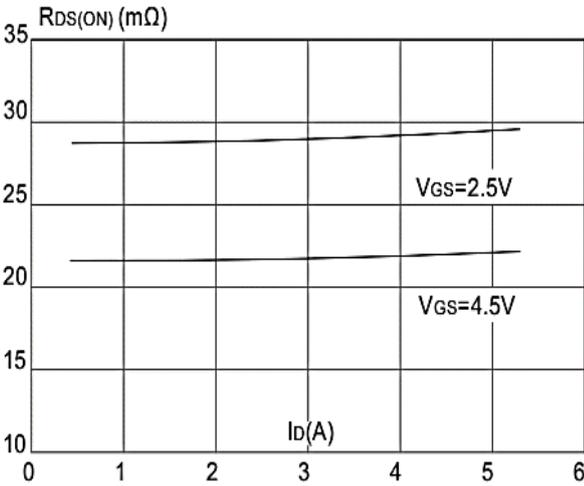
**Typical Characteristics**



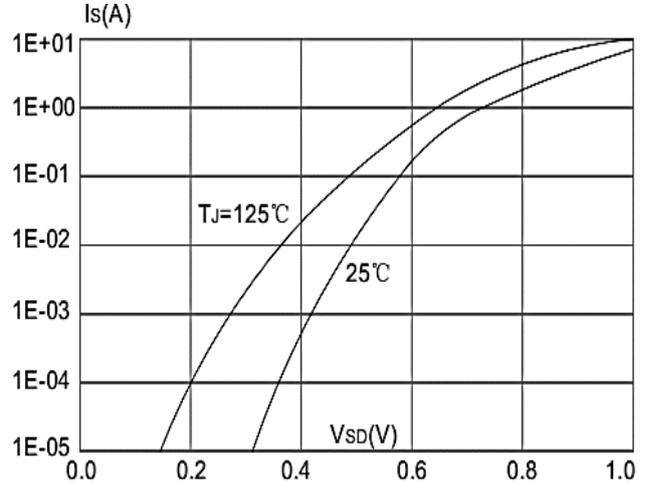
**Figure 1: Output Characteristics**



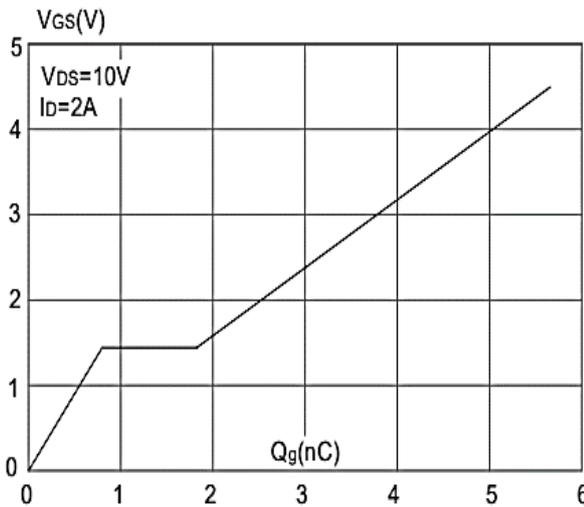
**Figure 2: Typical Transfer Characteristics**



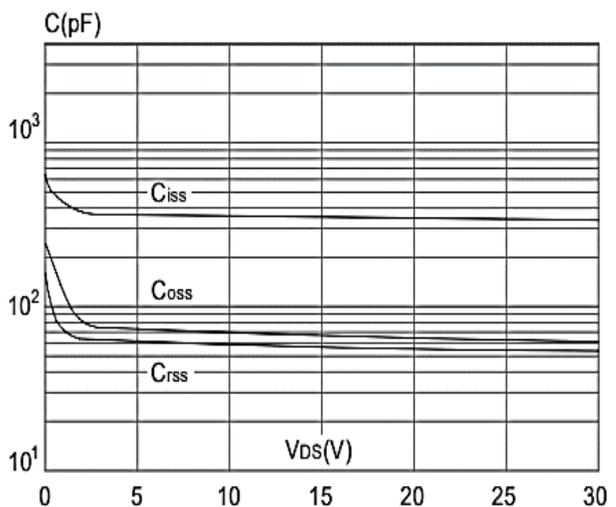
**Figure 3: On-resistance vs. Drain Current**



**Figure 4: Body Diode Characteristics**



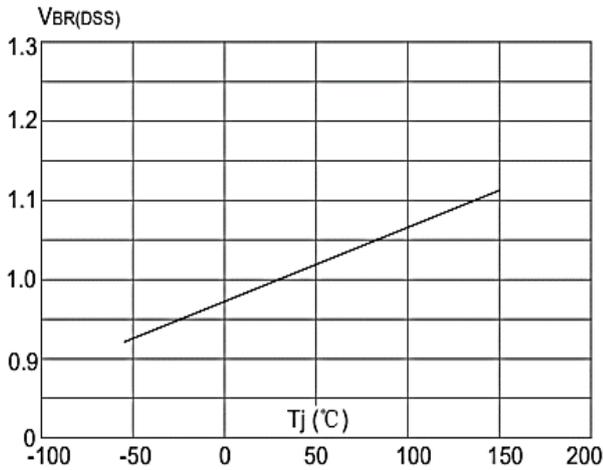
**Figure 5: Gate Charge Characteristics**



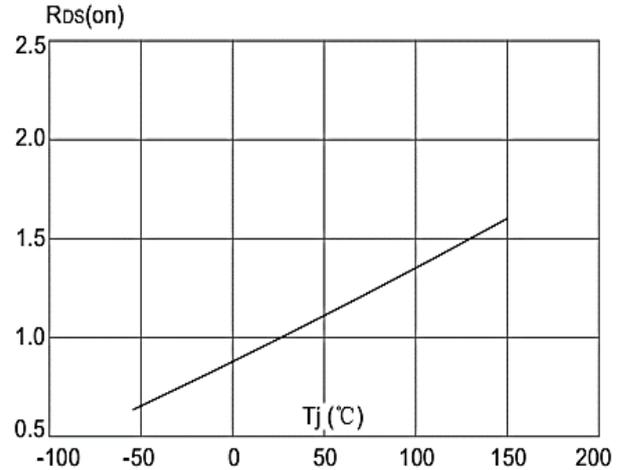
**Figure 6: Capacitance Characteristics**



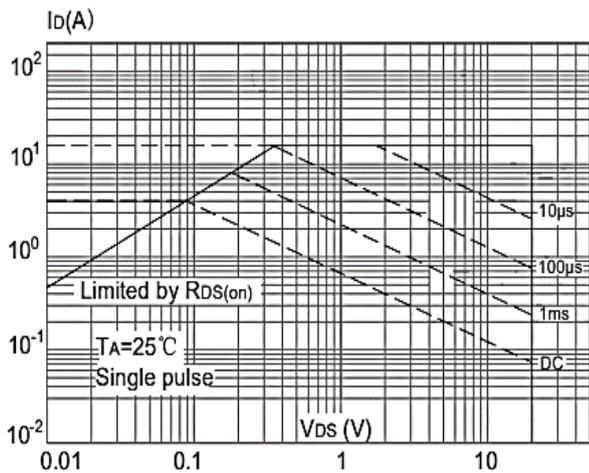
**20V N+N-Channel Enhancement Mode MOSFET**



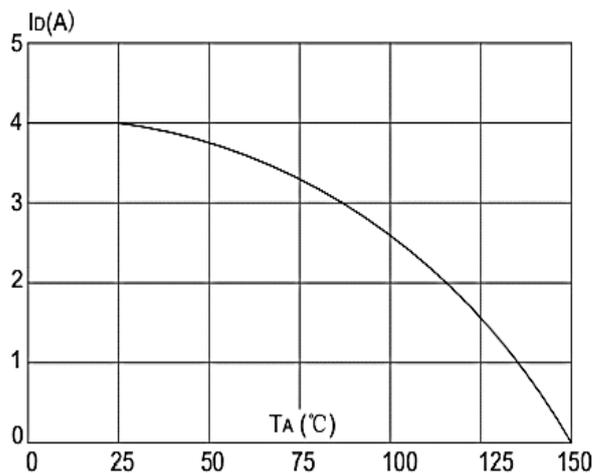
**Figure 7: Normalized Breakdown Voltage vs Junction Temperature**



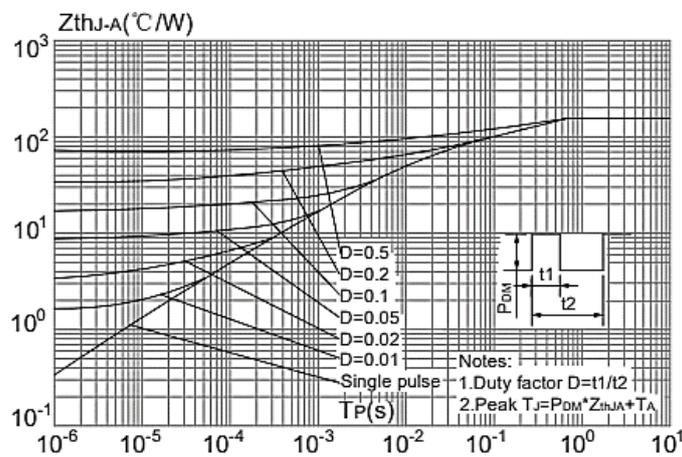
**Figure 8: Normalized on Resistance vs. Junction Temperature**



**Figure 9: Maximum Safe Operating Area**

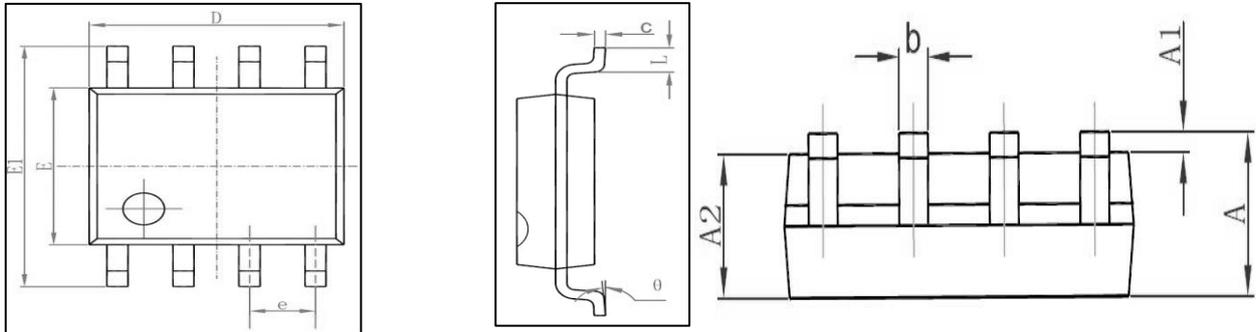


**Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature**

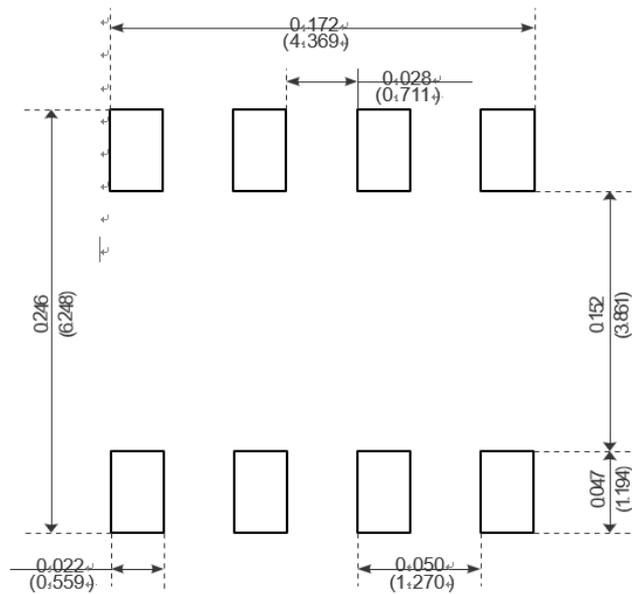


**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien**

### Package Mechanical Data-SOP-8L



| Symbol | Dimensions In Millimeters |       | Dimensions In Inches |       |
|--------|---------------------------|-------|----------------------|-------|
|        | Min                       | Max   | Min                  | Max   |
| A      | 1.350                     | 1.750 | 0.053                | 0.069 |
| A1     | 0.100                     | 0.250 | 0.004                | 0.010 |
| A2     | 1.350                     | 1.550 | 0.053                | 0.061 |
| b      | 0.330                     | 0.510 | 0.013                | 0.020 |
| c      | 0.170                     | 0.250 | 0.006                | 0.010 |
| D      | 4.700                     | 5.100 | 0.185                | 0.200 |
| E      | 3.800                     | 4.000 | 0.150                | 0.157 |
| E1     | 5.800                     | 6.200 | 0.228                | 0.244 |
| e      | 1.270 (BSC)               |       | 0.050 (BSC)          |       |
| L      | 0.400                     | 1.270 | 0.016                | 0.050 |
| θ      | 0°                        | 8°    | 0°                   | 8°    |



Recommended Minimum Pads

**20V N+N-Channel Enhancement Mode MOSFET****Attention**

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| Edition | Date     | Change          |
|---------|----------|-----------------|
| RVE1.0  | 2018/6/1 | Initial release |

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